

SEMICONDUCTOR TEST SYSTEM WITH TIME CRITICAL SEQUENCE
GENERATION USING GENERAL PURPOSE OPERATING SYSTEM

Abstract of the Disclosure

A semiconductor test system is capable of time critical
5 sequence generation using a general purpose operating system.
The semiconductor test system includes a tester hardware for
providing power sources and test patterns to a device under
test, a host computer operated by a general purpose operating
system, a configuration software for computing configuration
10 data and timing data based on a test program, a device driver
for providing a power trigger and a signal trigger to the
tester hardware, and a hardware timer for producing an
interrupt signal. The device driver causes to start the test
pattern and to deactivate the power sources upon receiving
15 the interrupt signal.

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